

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASA-1022-03	SERIAL NO.
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		APPLICANT S. HANZAWA et al	
		FILING DATE 12/04/03	GROUP 2818

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
TL	AA 5,793,697	08/11/98	Scheuerlein	—	—	—
TL	AB 6,314,014	11/06/01	Lowrey et al	—	—	—
TL	AC 5,258,958	11/1993	Iwahashi et al	—	—	—
TL	AD 5,226,014	07/1993	McManus	—	—	—
TL	AE 5,410,509	04/1995	Morita	—	—	—
TL	AF 5,508,960	04/1996	Pinkham	—	—	—
TL	AG 4,758,995	07/1988	Sato	—	—	—
AH						
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FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES <input type="checkbox"/> NO <input type="checkbox"/>
AL						<input type="checkbox"/> <input type="checkbox"/>
AM						<input type="checkbox"/> <input type="checkbox"/>
AN						<input type="checkbox"/> <input type="checkbox"/>
AO						<input type="checkbox"/> <input type="checkbox"/>
AP						<input type="checkbox"/> <input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

TL	AR	Scheuerlein, R., et al, "A 10ns Read and Write Non-Volatile Memory Array Using a Magnetic Tunnel Junction and FET Switch in each Cell", IEEE
		International Solid-State Circuits Conference, DIGEST OF TECHNICAL PAPERS, Feb 8, 2000, pp 128-131.
TL	AS	U.S. Patent Application Publication No. US 2001/0053104,
		Published Dec 20, 2001, Tran et al.
AT		

EXAMINER	Thoung	DATE CONSIDERED	8/26/04
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
ASA-1022-03SERIAL NO.
10/726,658LIST OF DOCUMENTS CITED BY APPLICANT
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S. HANZAWA et alFILING DATE
December 4, 2003GROUP
2818

JUN 30 2004

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
LC	AA 6,317,376	11/13/01	Tran et al	—	—	—
TL	AB 6,269,040	07/31/01	Reohr et al	—	—	—
AC						
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